

Atomic Layer Deposition of functional oxide perovskites ABO_3 on large surface: cases of $SrTiO_3$, $BiFeO_3$

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Flagship **AXION**: nAnoXITrONics

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ALD — Atomic Layer Deposition

Films

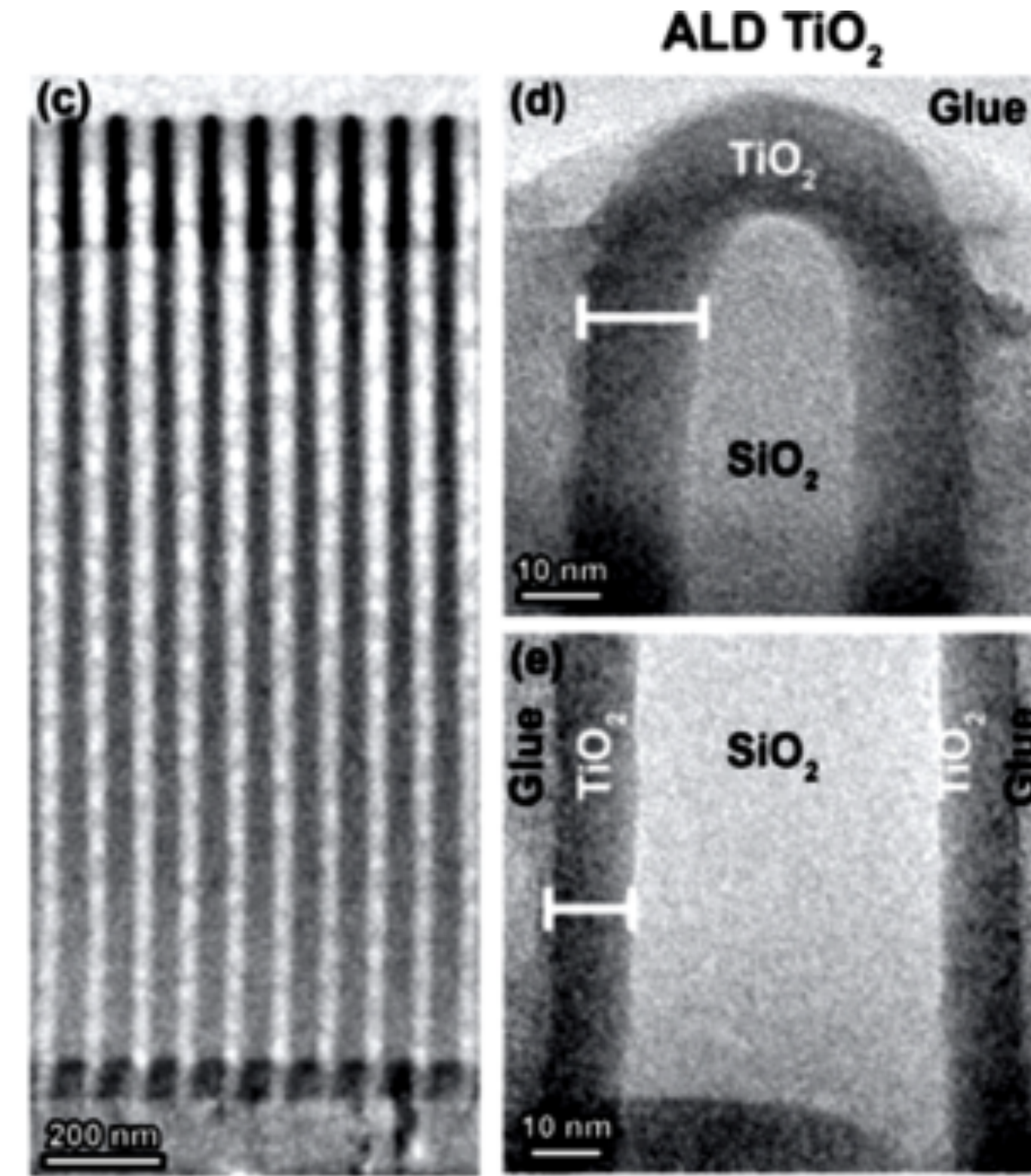
- Easy control of film thickness and stoichiometry
- Excellent repeatability
- 100% film density
- Complex heterostructure

Conformal Coating

- Excellent 3D conformity
- Large area thickness uniformity
- Atomically flat and smooth coating

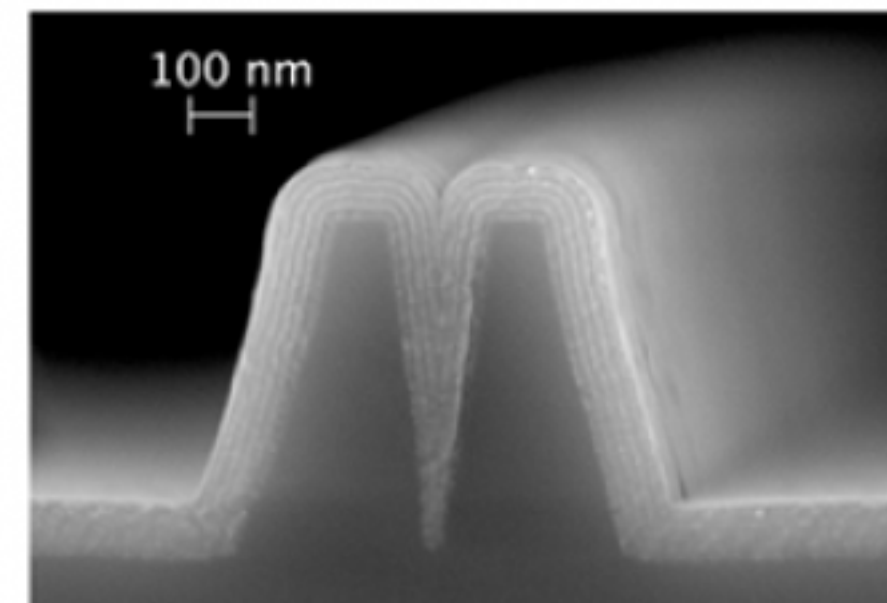
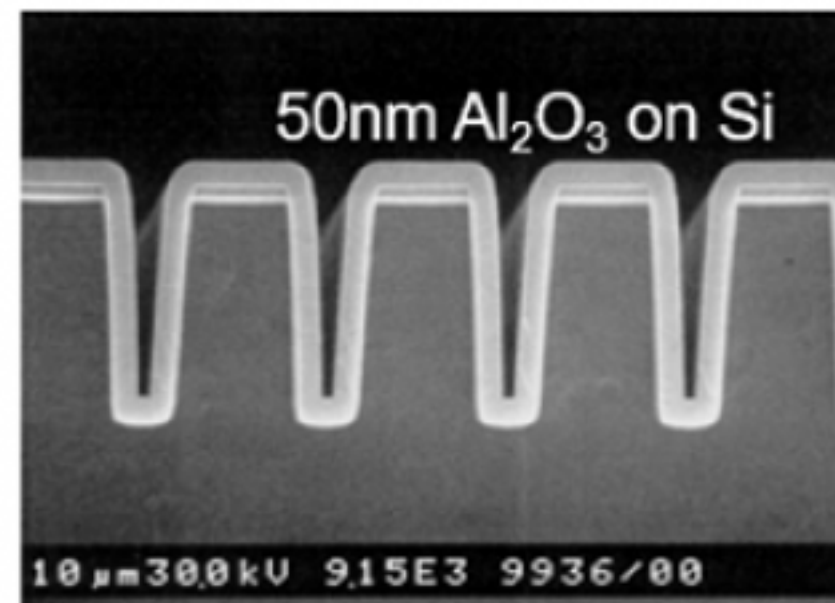
Challenging Substrates

- High aspect ratio materials
- Low temperature and low stress
- Batch process



P. Schindler, Langmuir 2015, 31, 5057

beneo



Already in industry for:

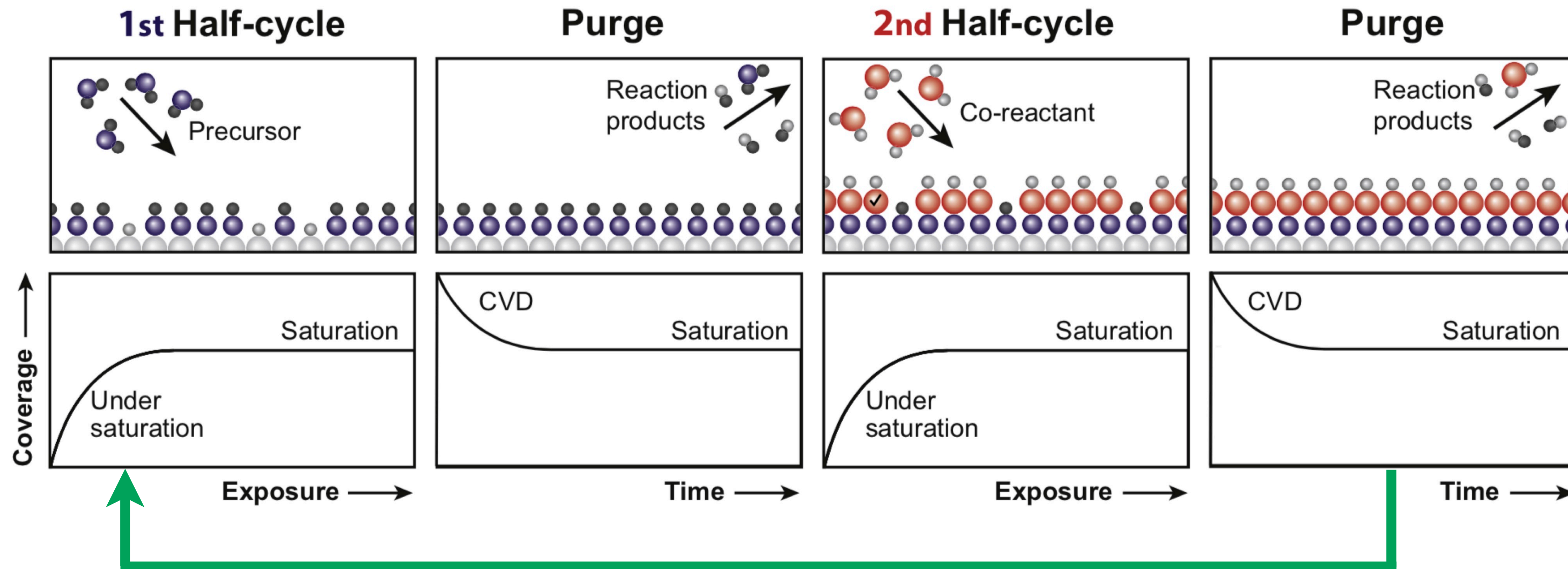
- Passivation, diffusion barrier layers (TiN, etc.)
- Dielectric, High-k layers (HfO₂, SrTiO₃, etc.)
- Electrodes (Al:ZnO, etc.)

Perspectives for:

- Photovoltaic, SOFC
- New architectures with high aspect ration (nanowires)
- 2D materials (graphene, chalcogenides, nitrides)

ALD — Atomic Layer Deposition. Principle

ALD is based on repeated self-terminating irreversible gas-solid reactions (chemisorption)

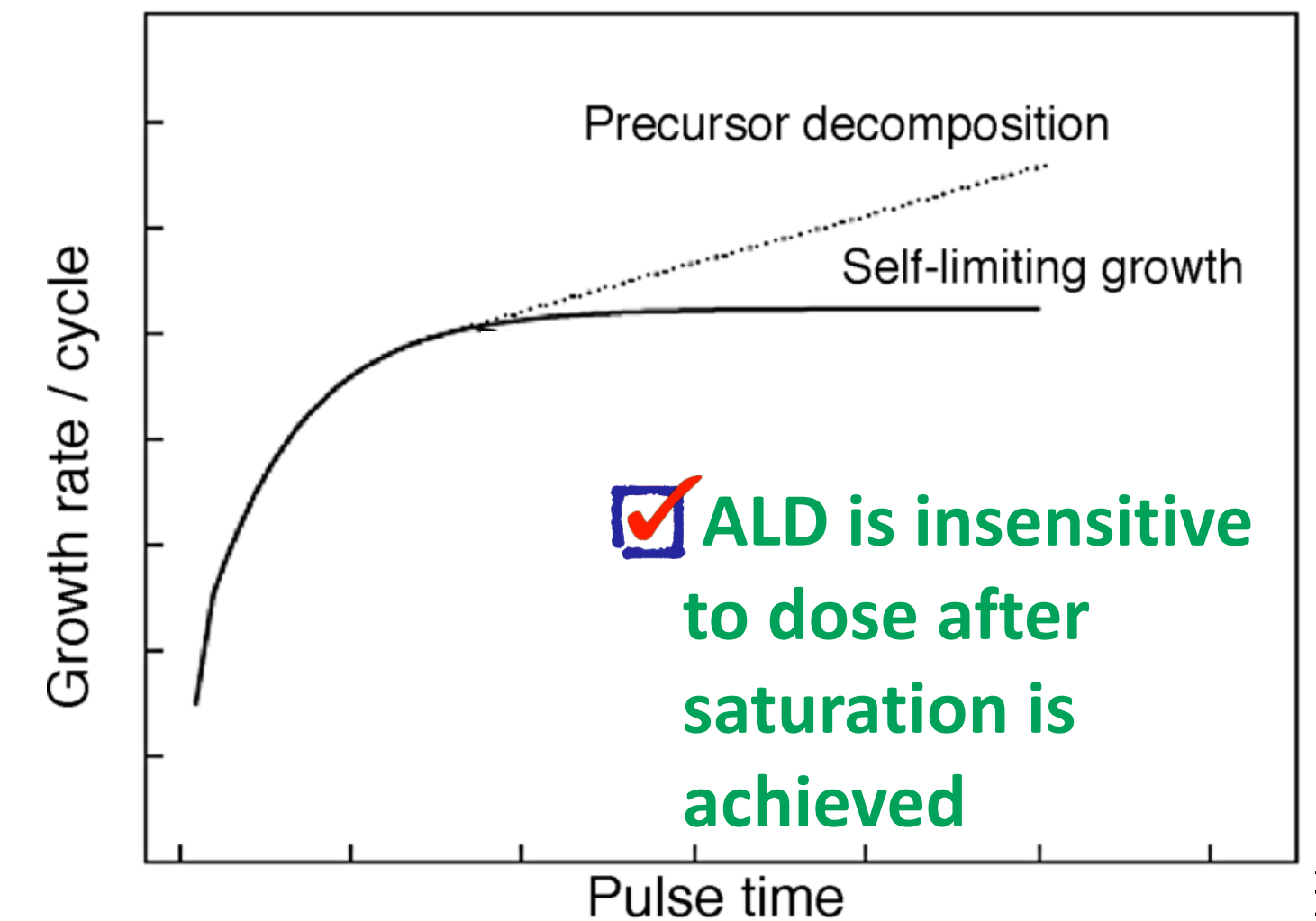
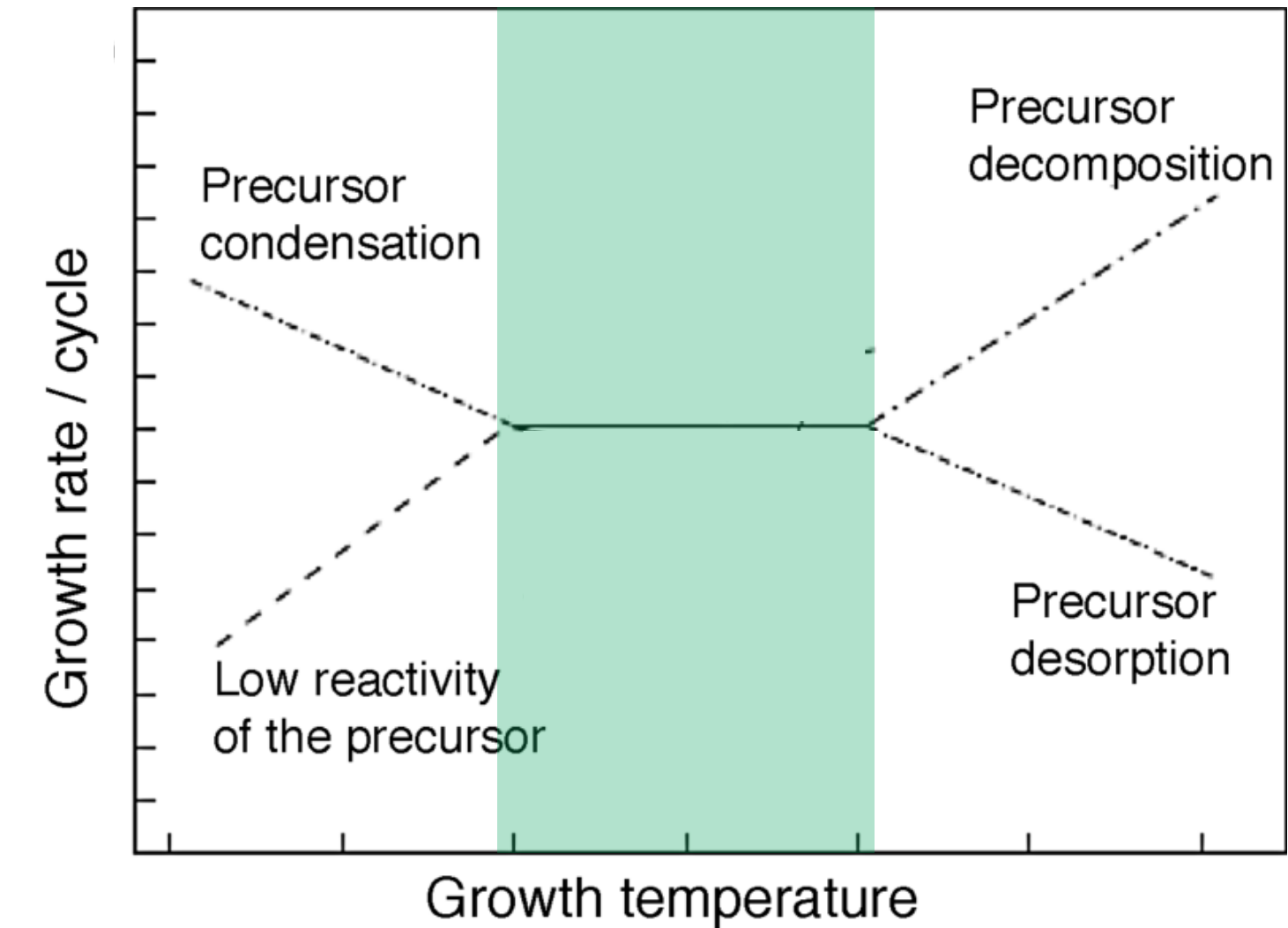


n cycles

↓

GPC — Growth per Cycle (Å/cycle)

ALD window (GPC is constant) :



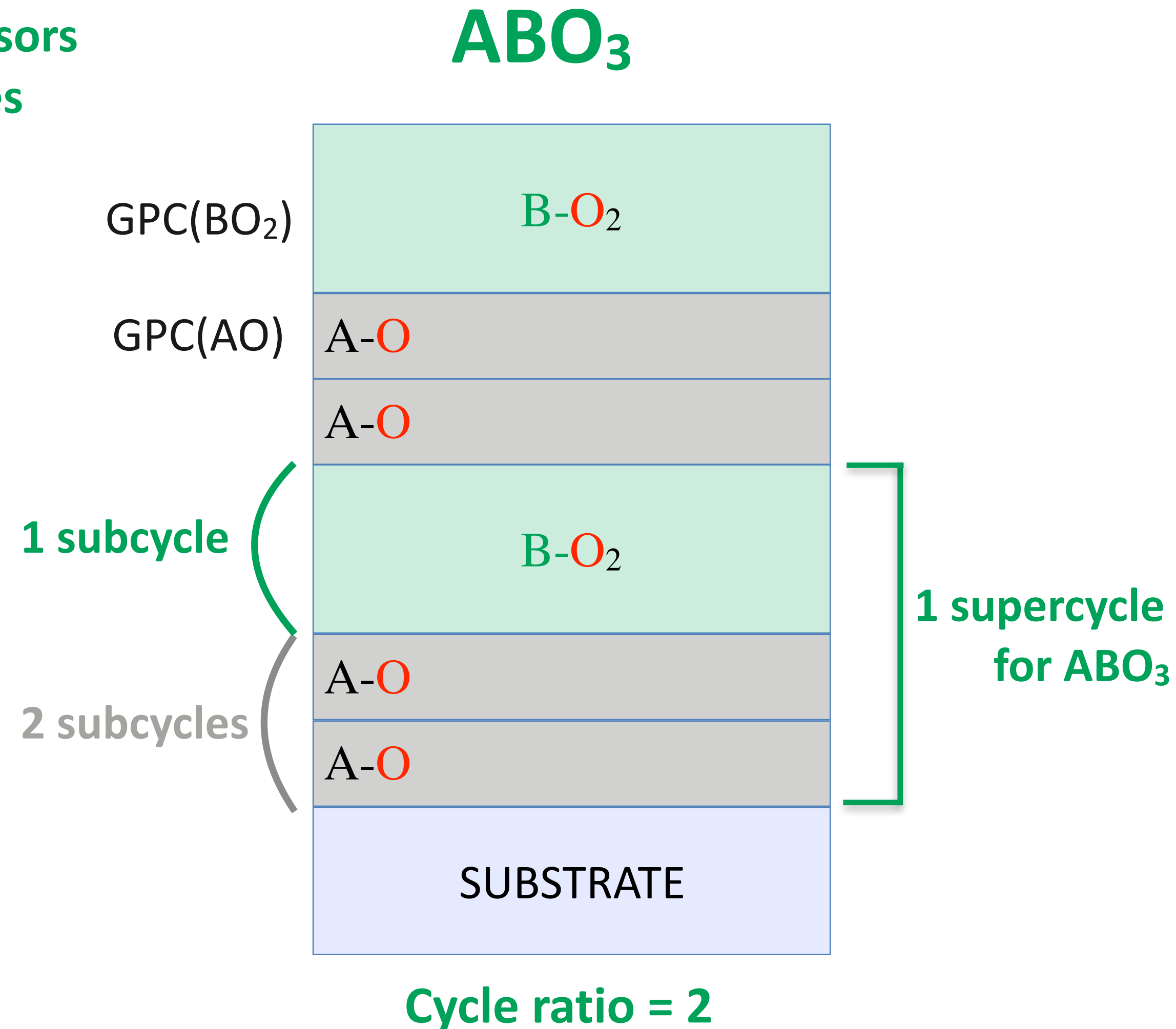
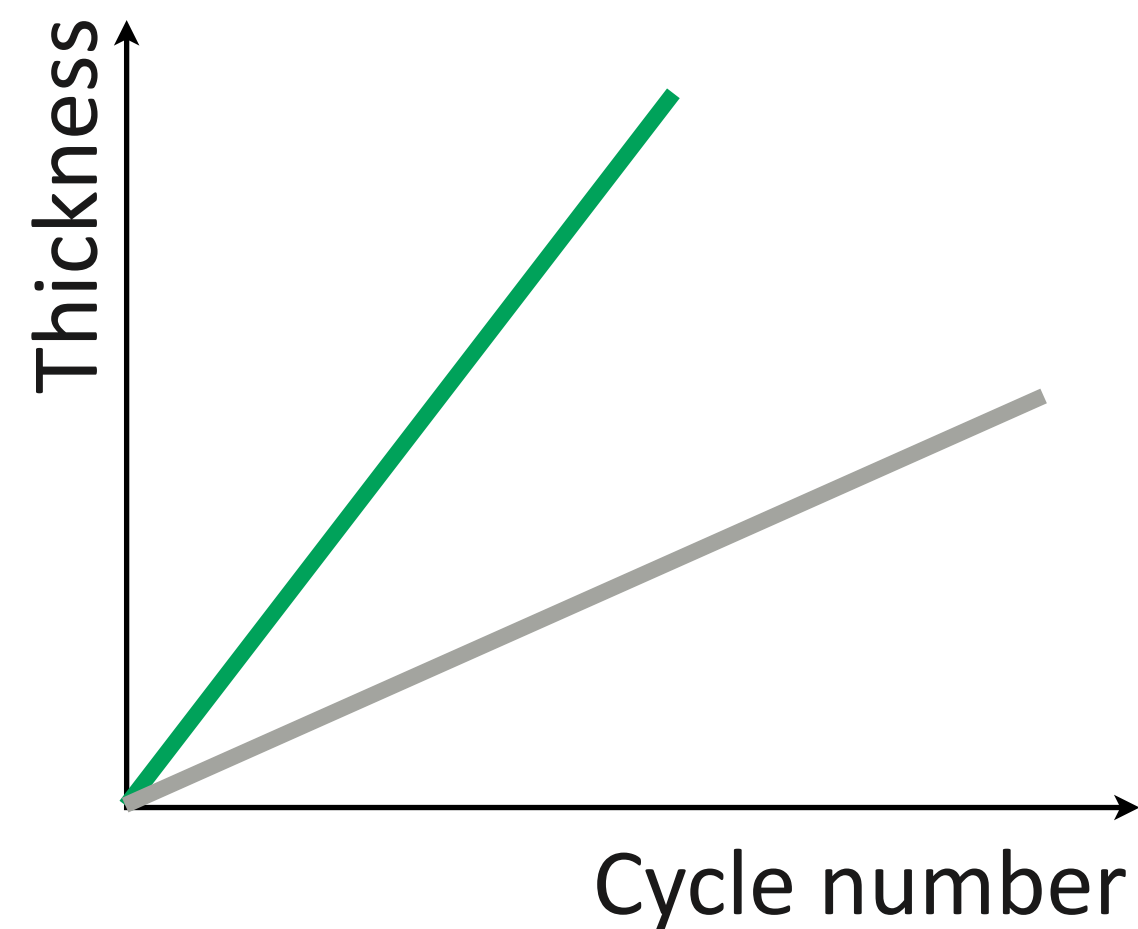
Synthesis of ternary materials by ALD

Supercycle approach

Supercycle approach involves the use of two metalorganic precursors that are dosed in separate cycles

This example:

$$\text{GPC}(\text{BO}_2) = 2 \cdot \text{GPC}(\text{AO})$$



Conditions:

- Compatible physico-chemical properties of the two precursors (evaporation temperature, adsorption kinetics)
- Compatible ALD windows (temperature range of linear growth rate)

ANNEALSYS MC-050 DLI-CVD/ALD machine

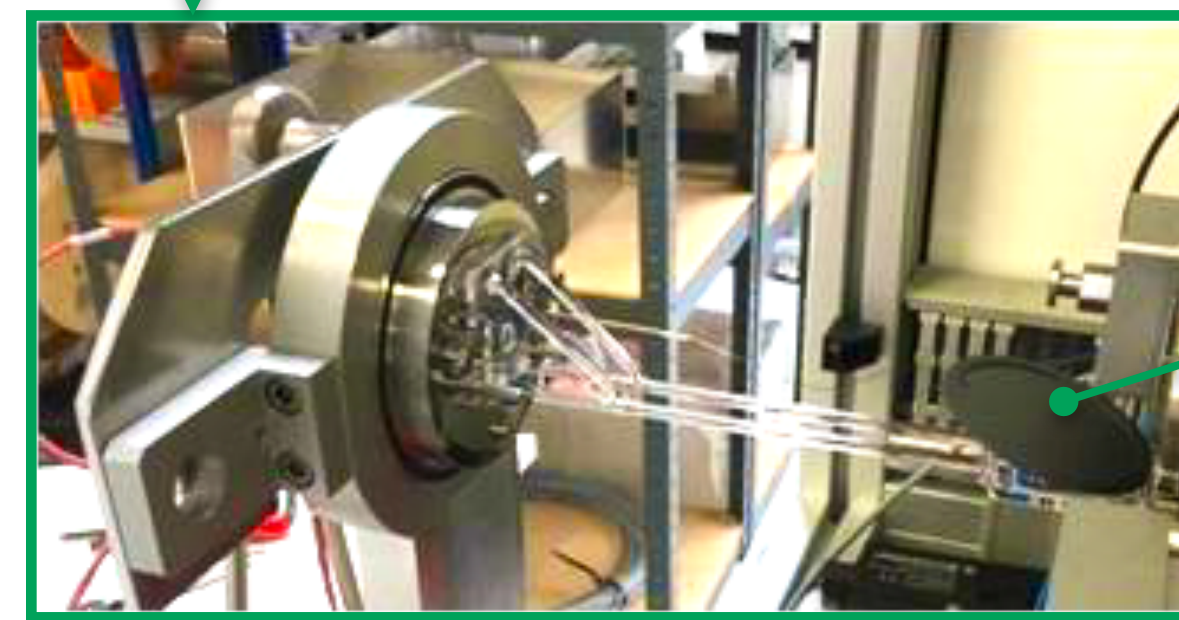
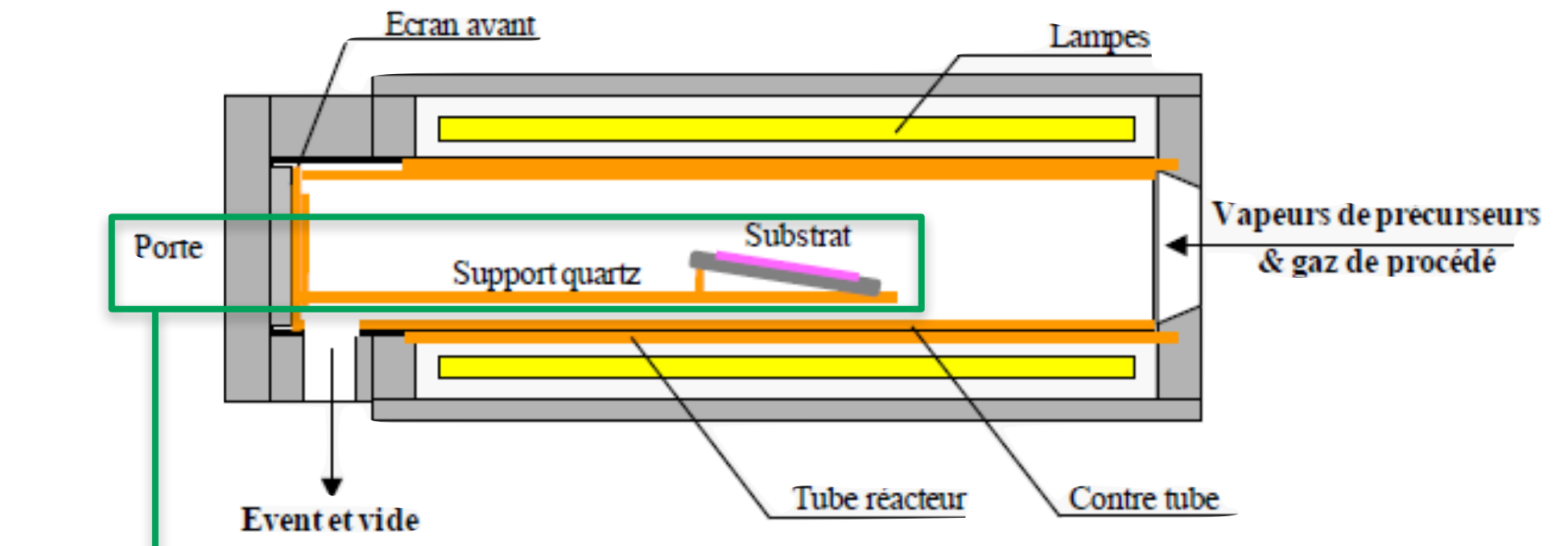
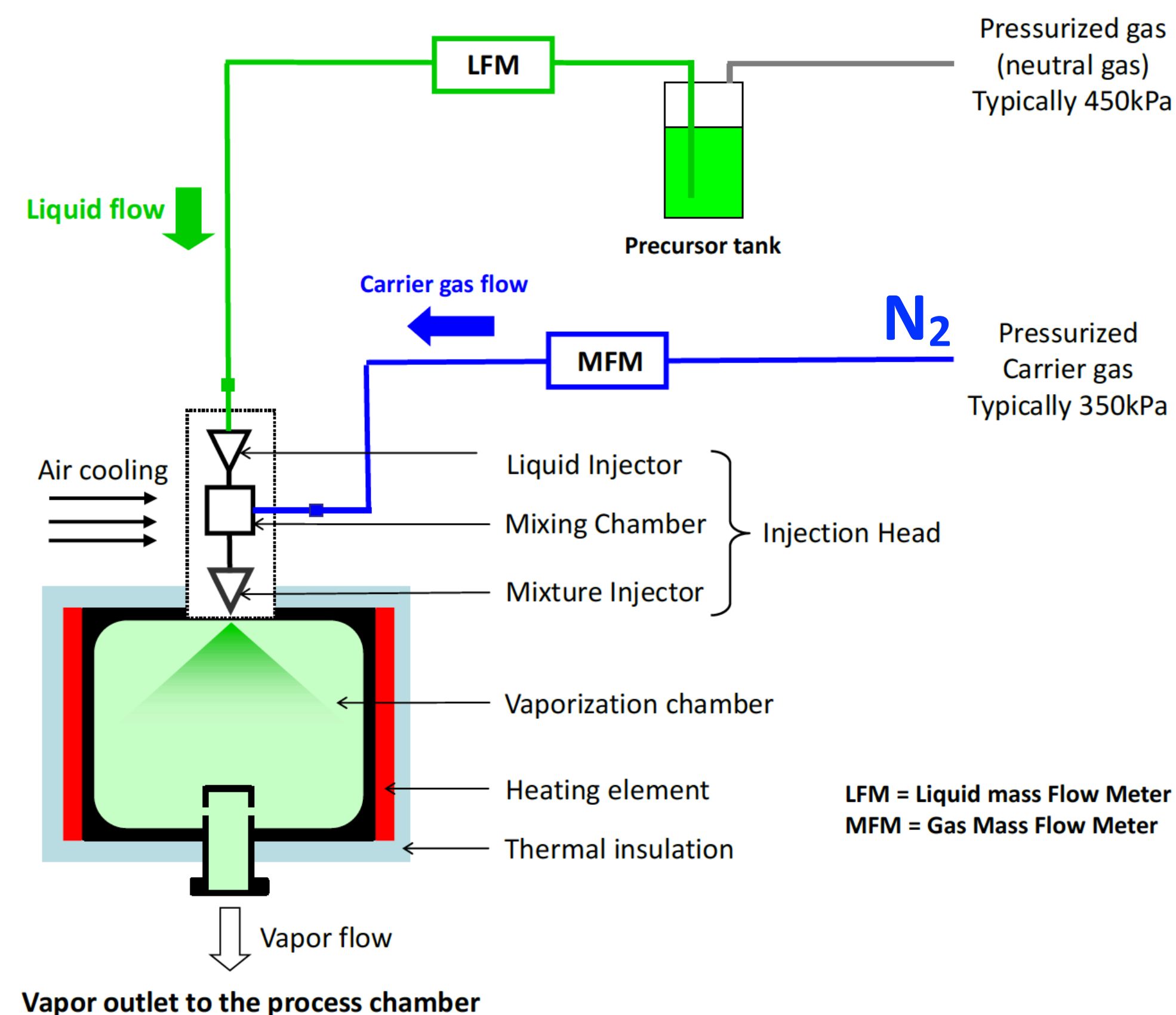
DLI — Direct Liquid Injection

Interest of the DLI:

- use of **diluted** chemical precursors
- use of precursors with **low vapor pressure**
- sources kept ambient temperature (stability)
- short pulse times (few ms fast DLI injectors)

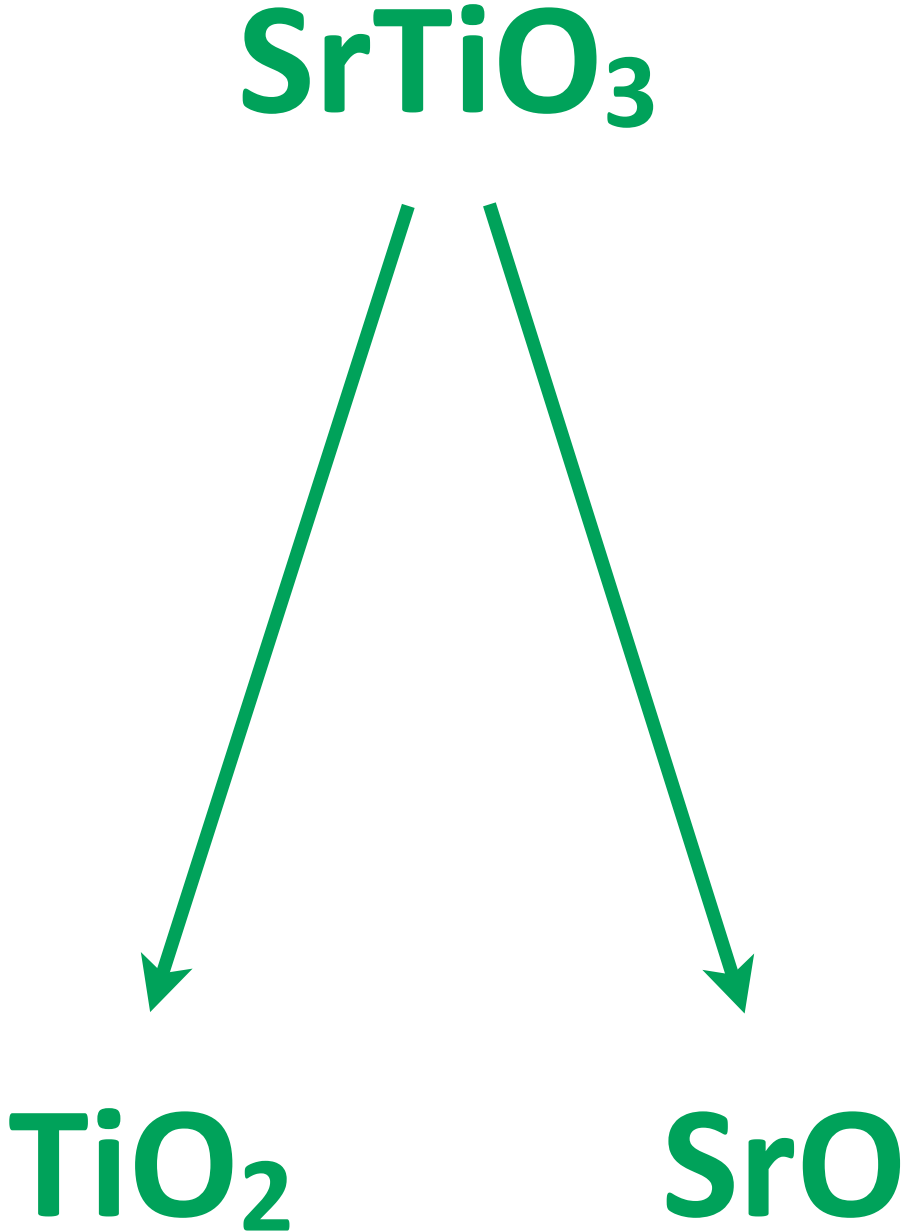
Process chamber:

- CVD, ALD, MOCVD, RTP and RTCVD
- **RTA to 1100°C**
- infrared lamp furnace
- atmosphere to 10^{-3} Torr
- **H₂O / O₃ / H₂** / remote plasma (optional)



2" substrate holder

Main results



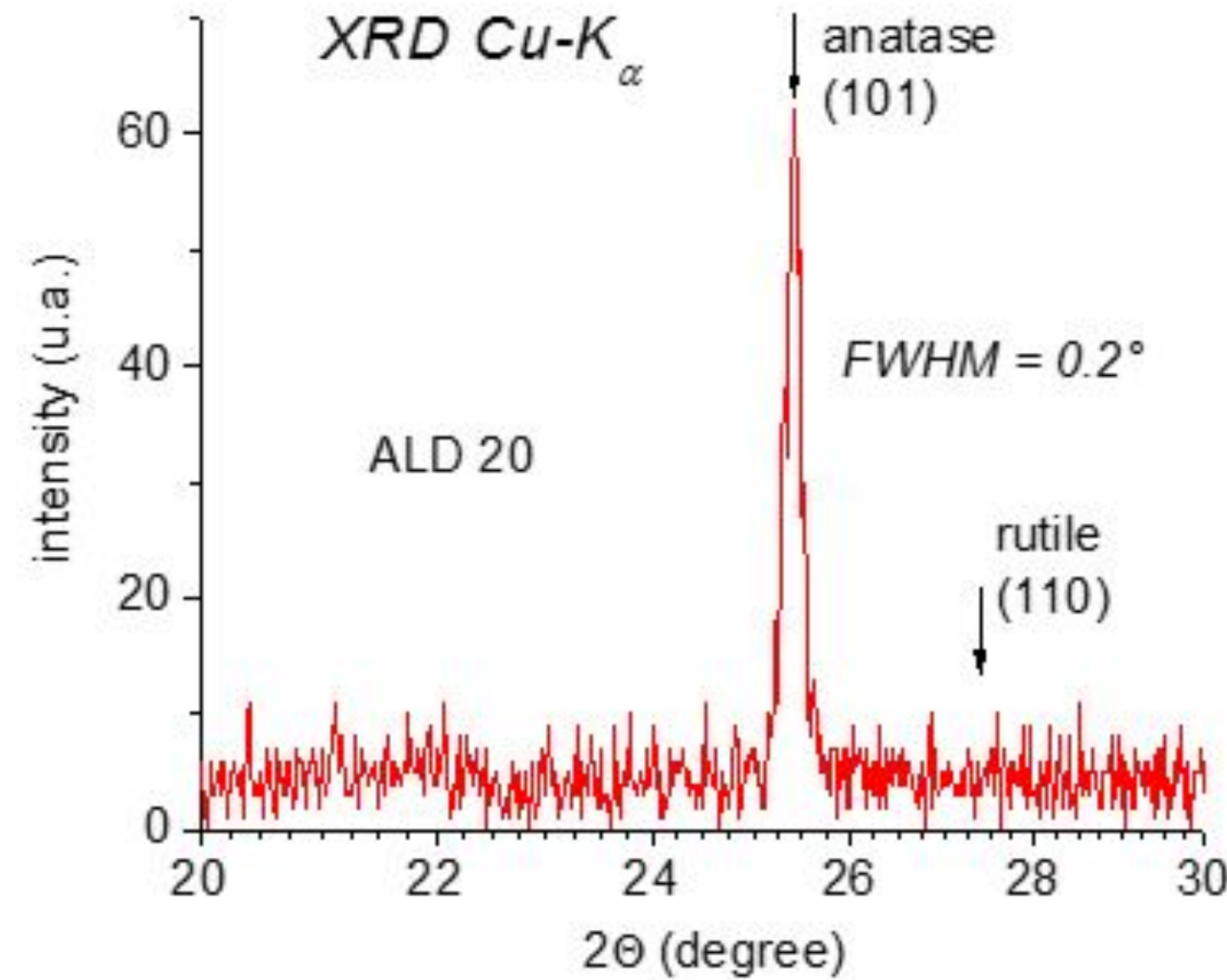
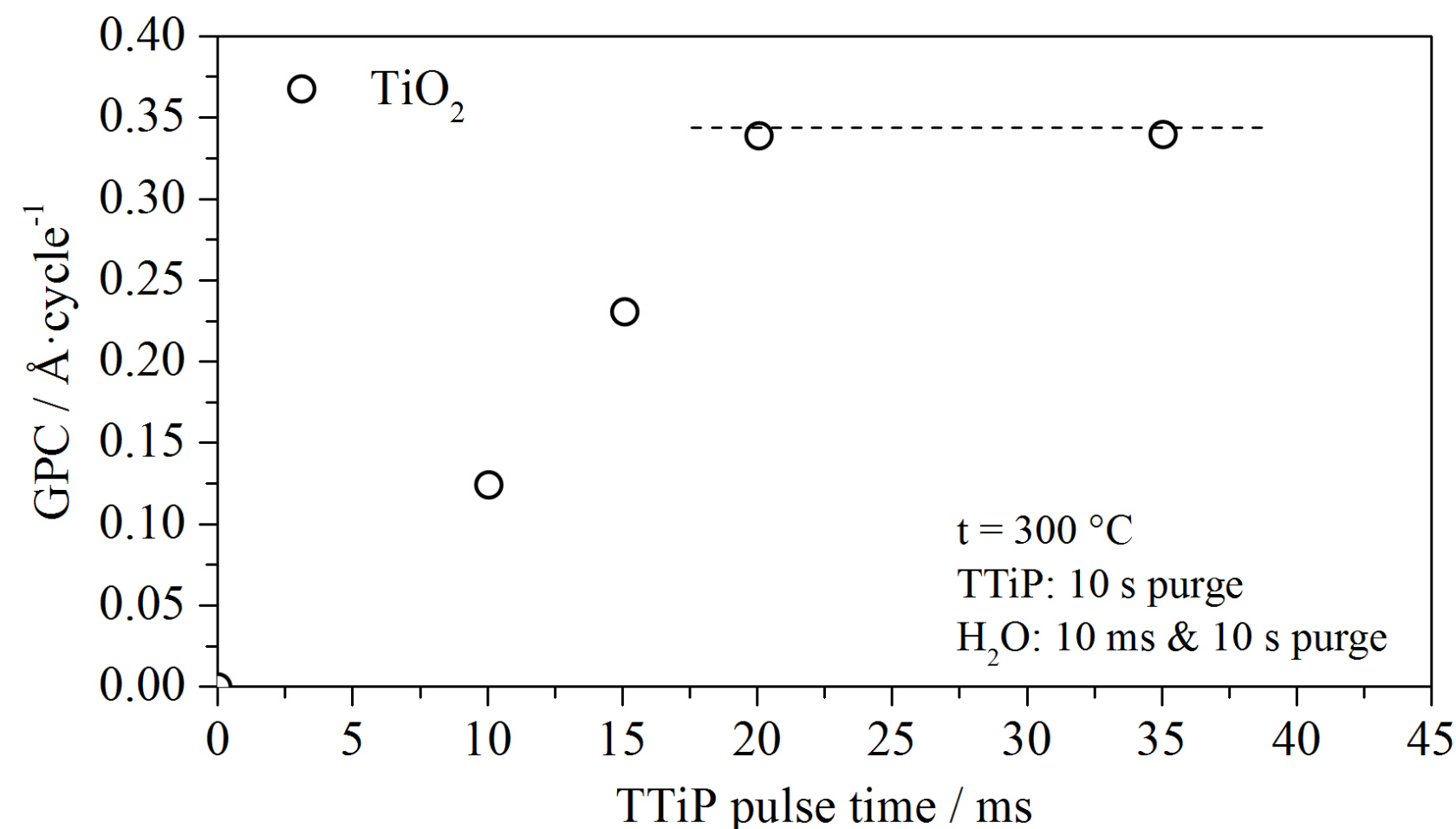
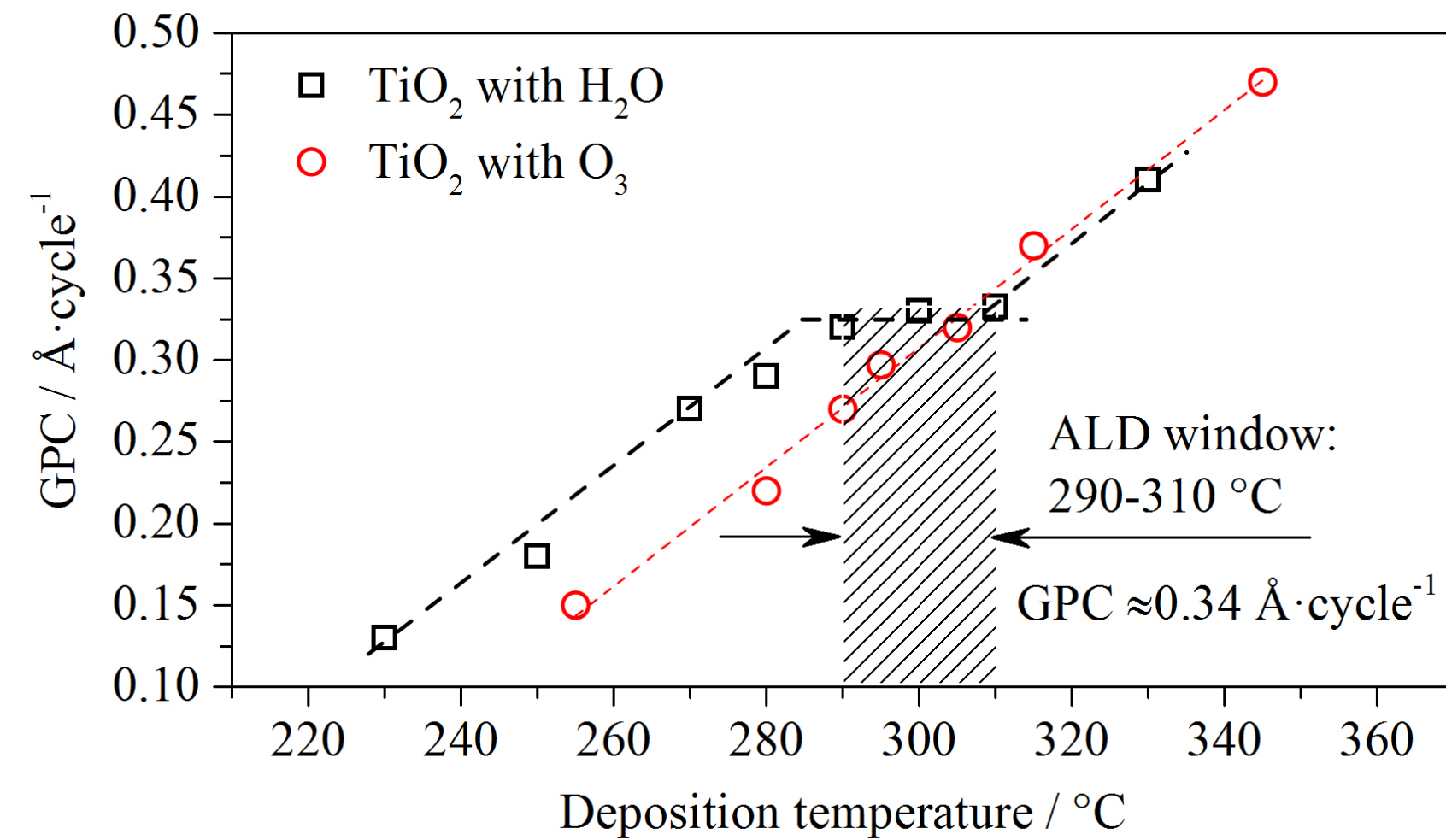
TiO₂ growth process optimization

Precursor solution:

- [TTiP]= $5 \cdot 10^{-3}$ M in toluene (C₆H₅CH₃)

TTiP — Ti[OCH(CH₃)₂]₄ titanium isopropoxide

Oxidizing agents: O₃ or H₂O

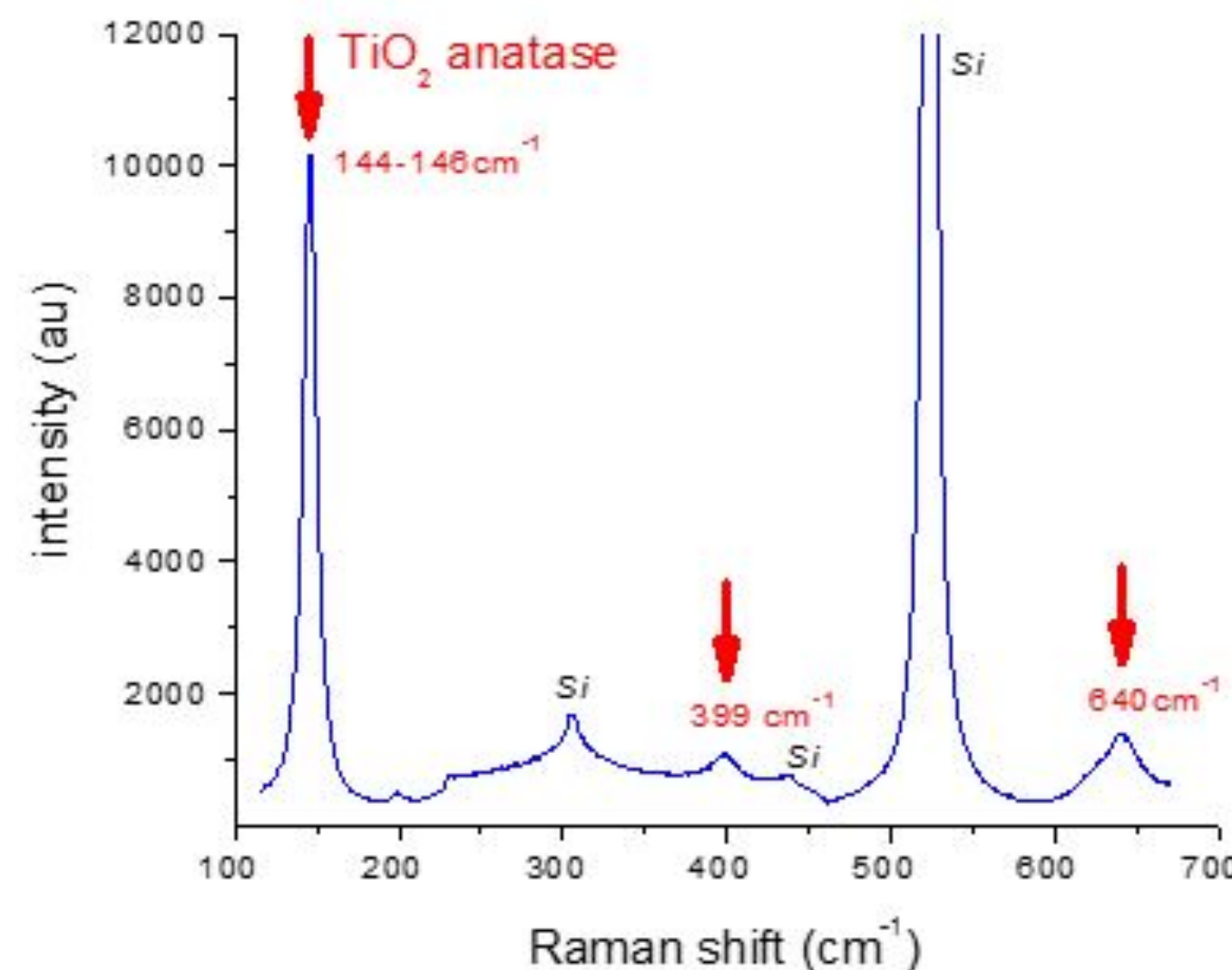


Ellipsometry measurements (thickness/RMS):



TiO₂ with H₂O :

- cristalline as grown: anatase phase
- well covered film
- high thickness homogeneity (<5% variation)
- low roughness (R_q ≈ 4 nm by AFM)
- no carbon contamination (by XPS)



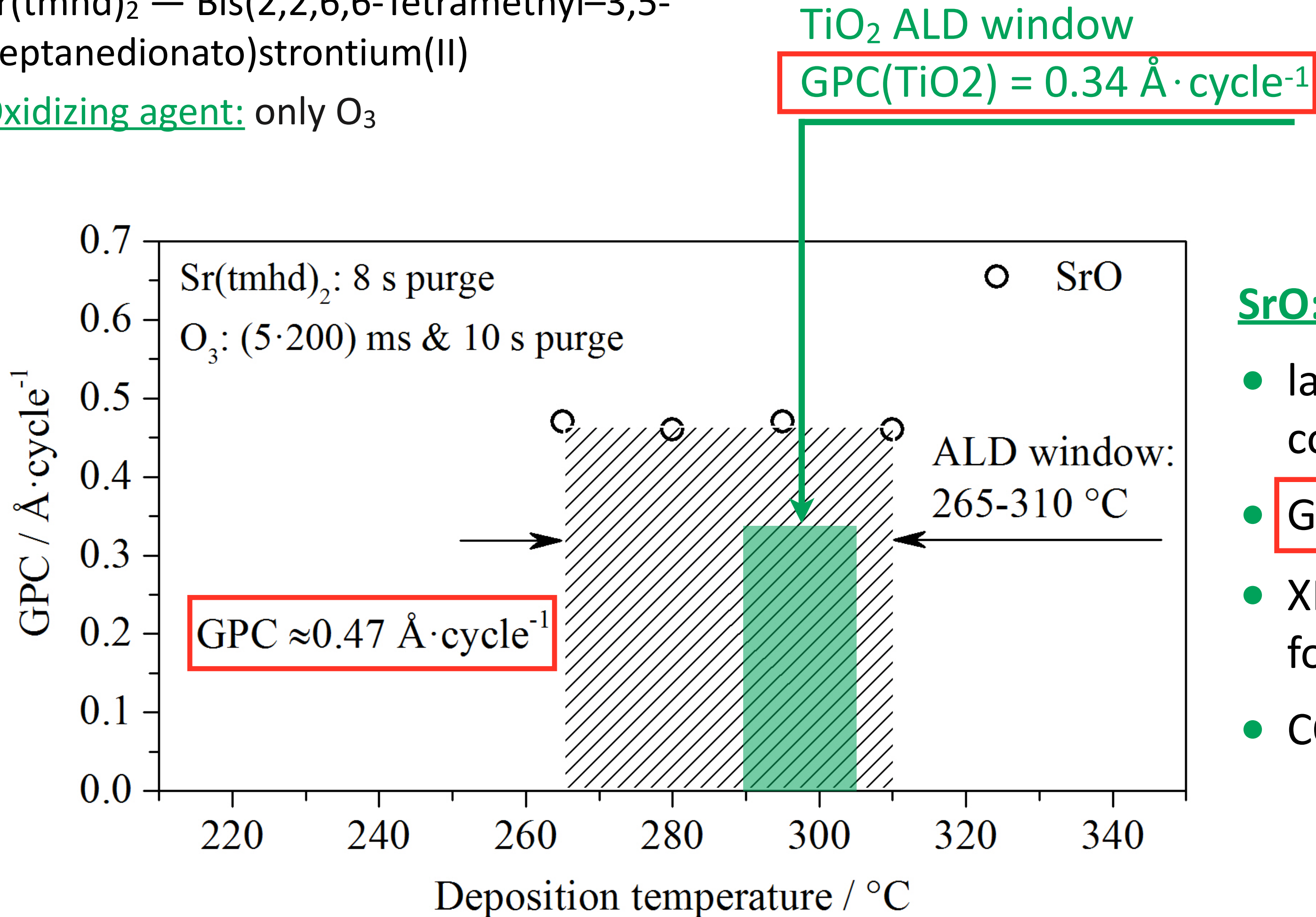
SrO growth process optimization

Precursor solution:

- $[\text{Sr}(\text{tmhd})_2] = 5 \cdot 10^{-3} \text{ M}$ in toluene ($\text{C}_6\text{H}_5\text{CH}_3$)

$\text{Sr}(\text{tmhd})_2$ — Bis(2,2,6,6-Tetraméthyl-3,5-heptanedionato)strontium(II)

Oxidizing agent: only O_3



SrO:

- large ALD window (min. 265-310 $^\circ\text{C}$) compatible with TiO_2
- $\text{GPC}(\text{SrO}) = 1.4 \cdot \text{GPC}(\text{TiO}_2)$
- XPS: high carbon content (partial SrCO_3 formation ?)
- CO_3^{2-} to be removed with H_2O injection

SrTiO₃ growth. ALD supercycle approach

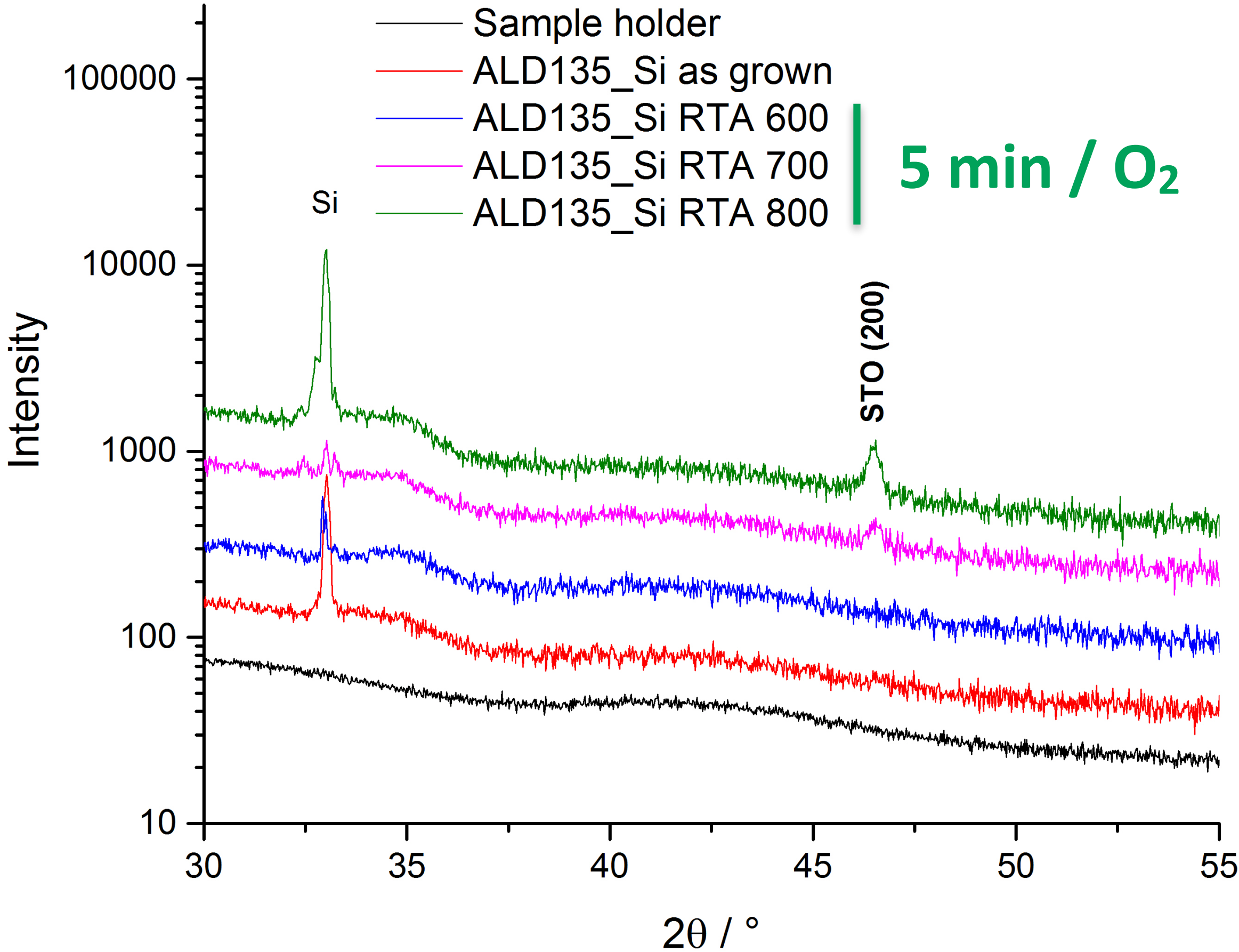
Input: $GPC(SrO) = 1.4 \cdot GPC(TiO_2)$

SrTiO₃ growth at 295 °C :

Cycle ratio Ti : Sr	Thickness, nm	Cation elementary composition (Ti : Sr), %at.
2 : 1	80	58 : 42
1 : 1	77	45 : 55
3 : 2	56	65 : 35

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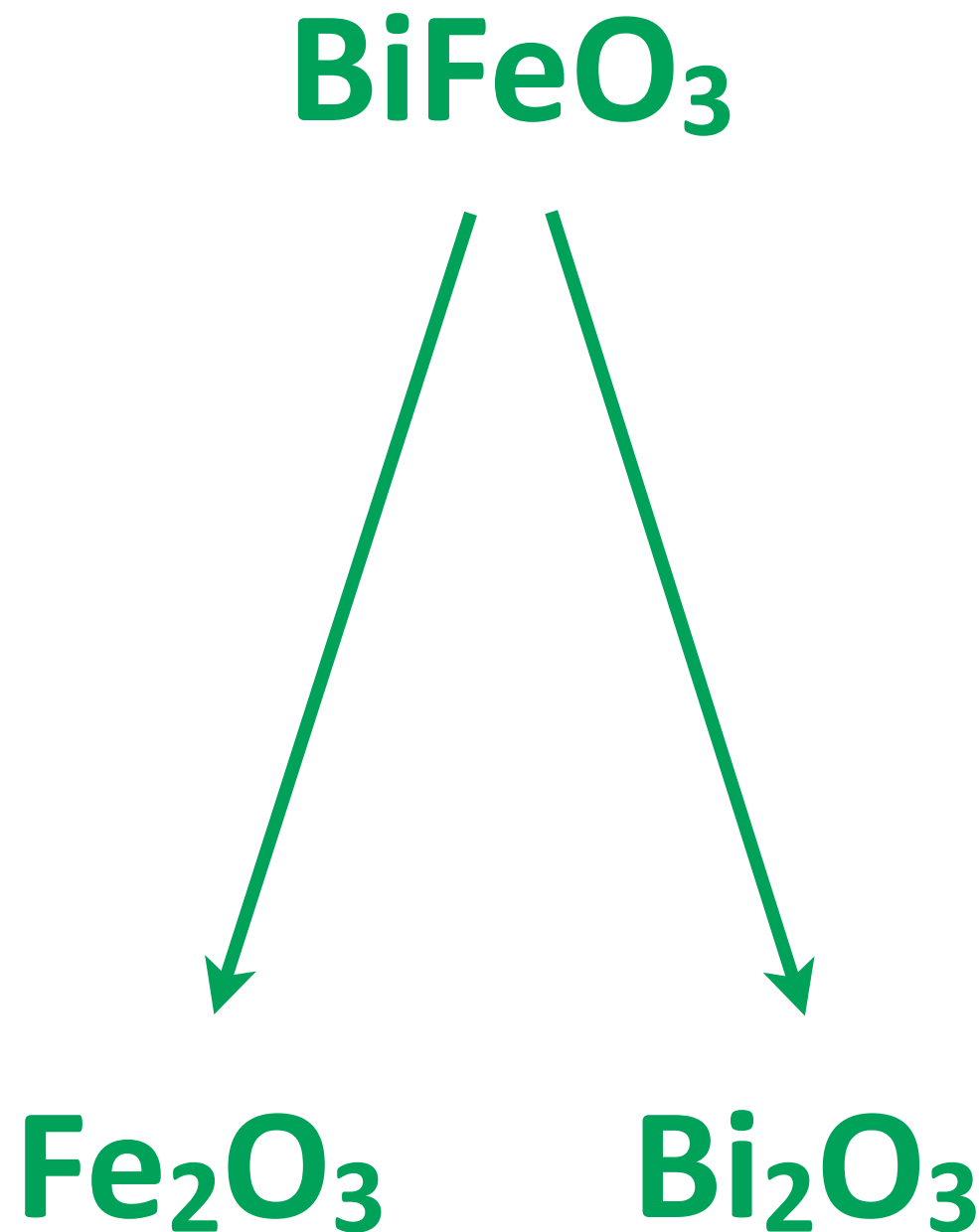
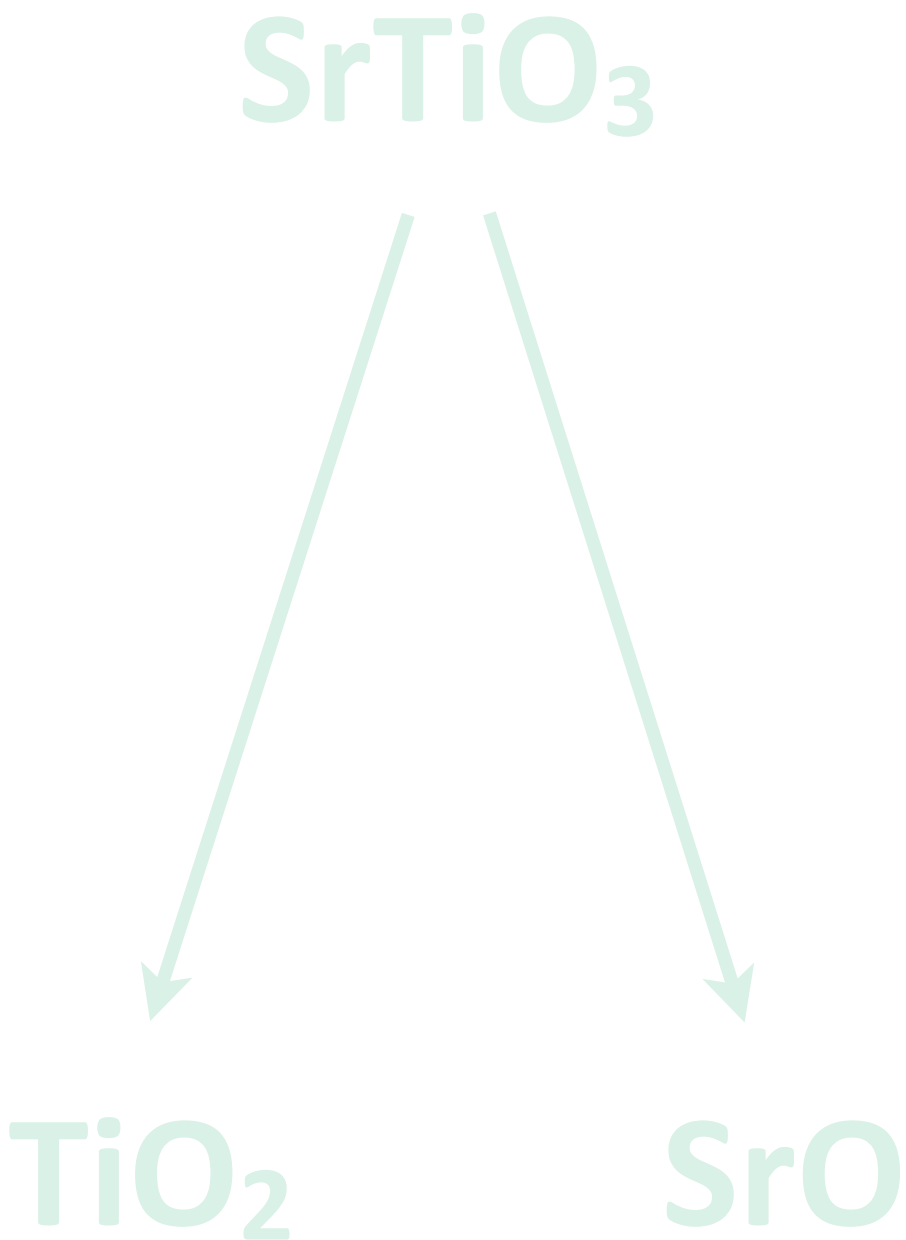
by XPS



- amorphous as grown STO/Si(100) or STO/LAO
- further annealing is required to crystallize
- Sr excess leads to more easy crystallization of STO
- no carbon contamination (by XPS)



Main results



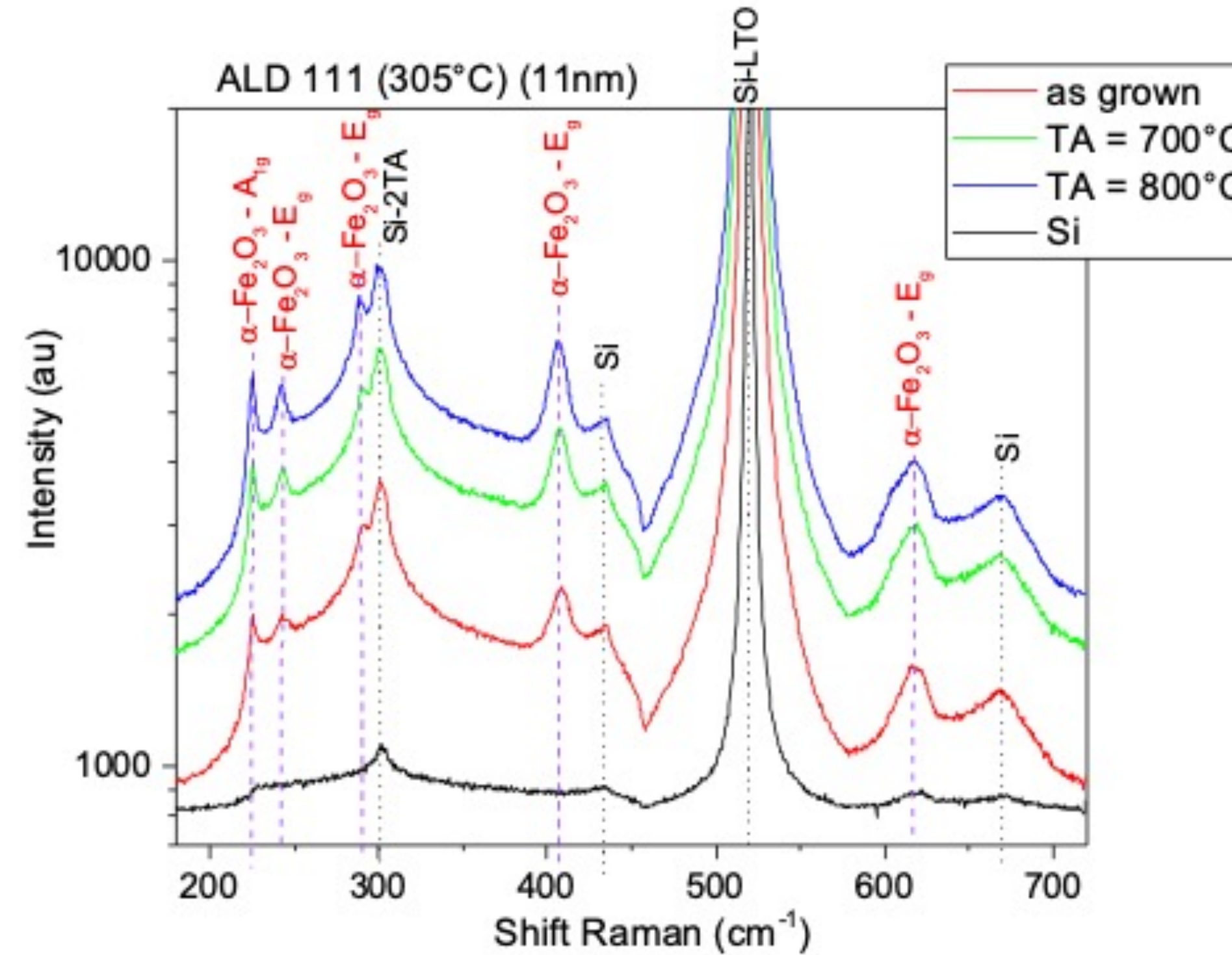
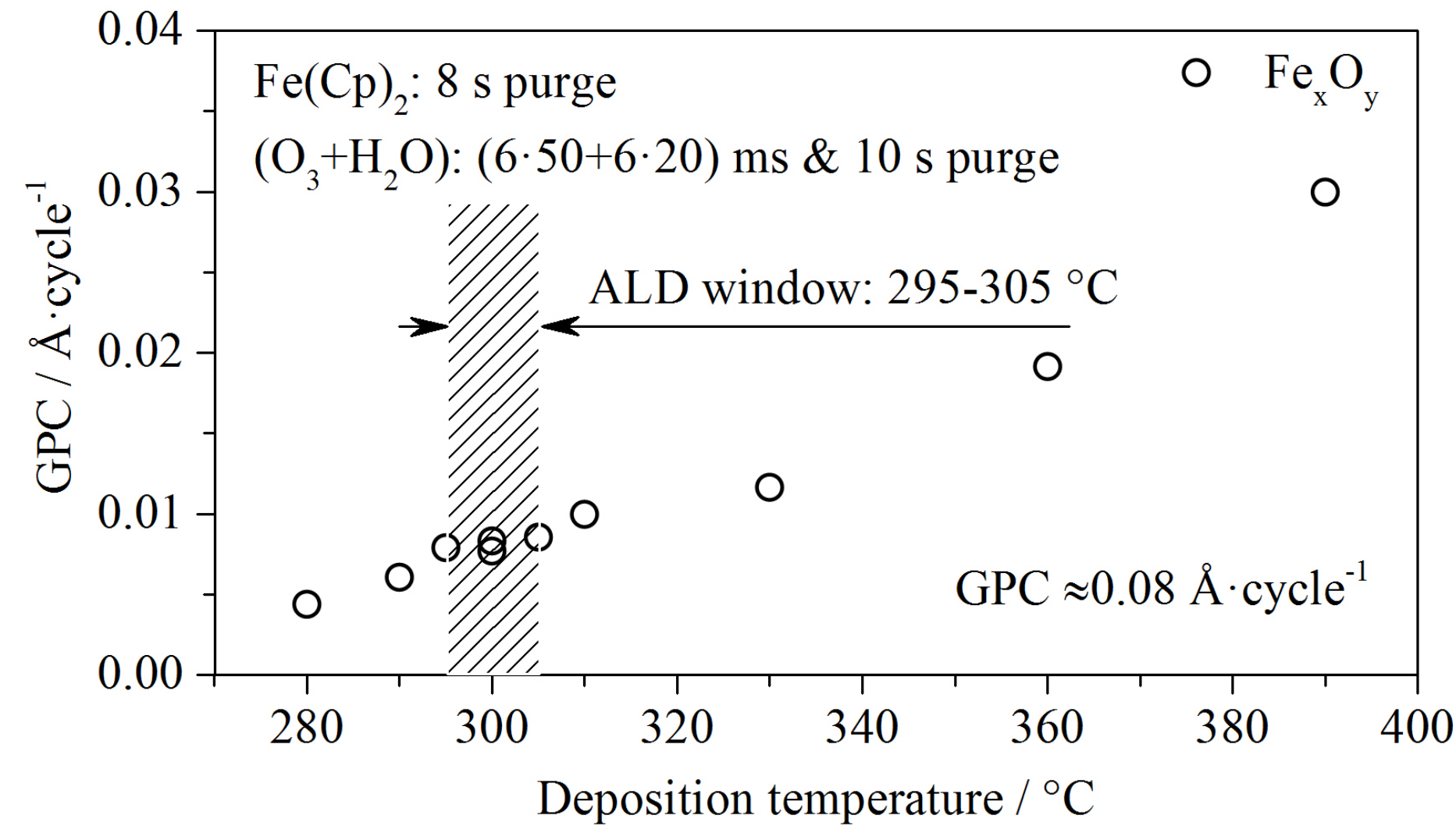
Fe₂O₃ growth process optimization

Precursor solution:

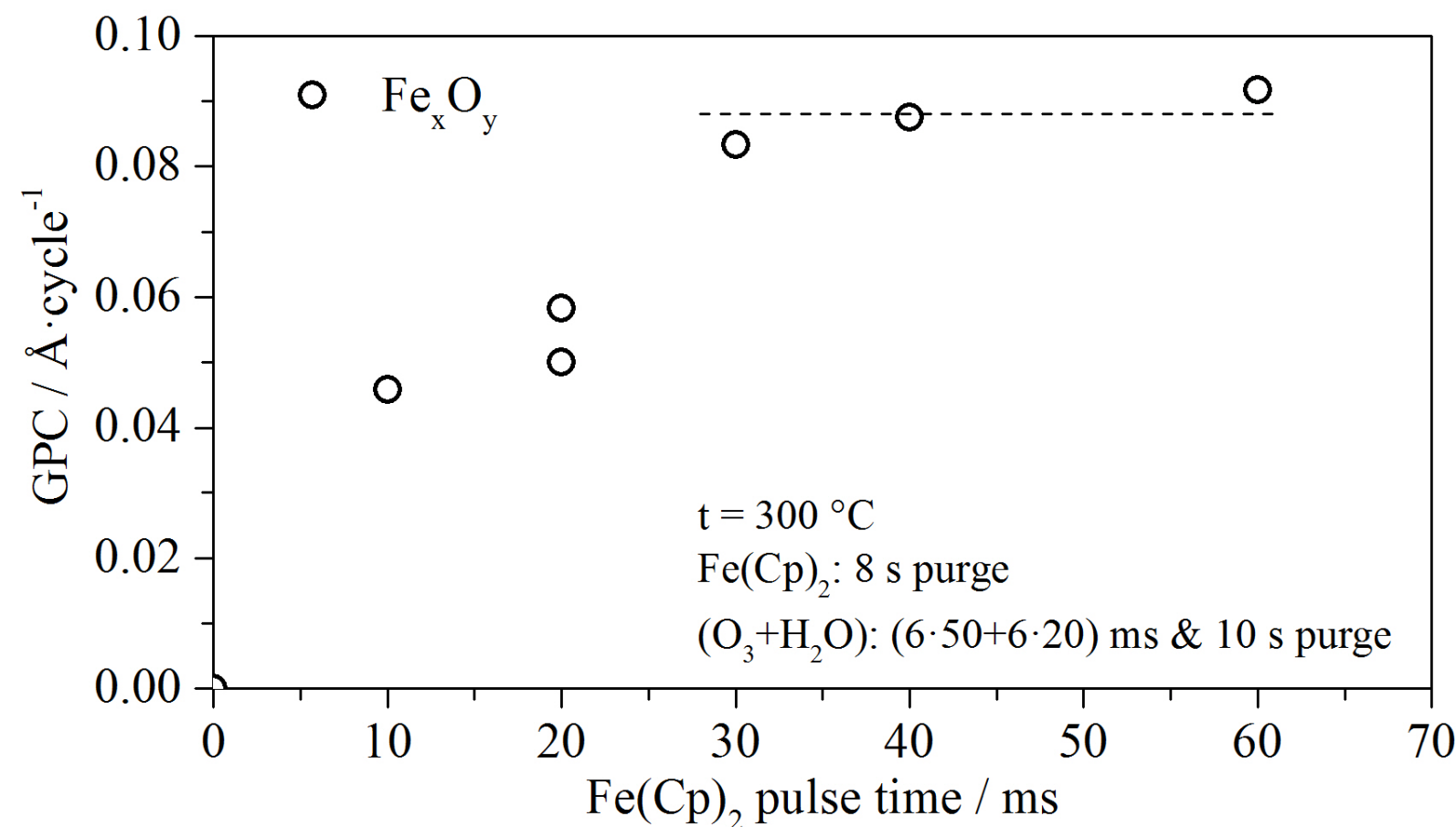
- [Fe(Cp)₂] = 6 · 10⁻³ M in toluene (C₆H₅CH₃)

Fe(Cp)₂ — Fe(C₅H₅)₂ ferrocene

Oxidizing agents: O₃ & H₂O



XPS: O/Fe = 1.325
(1.5 expected for Fe₂O₃)



- growth rate (GPC) is extremely slow
- Raman: α-Fe₂O₃ phase without annealing
- XPS: no carbon contamination

Name	Peak BE	FWHM eV	Area (P) CPS.eV	Atomic %
Fe2p3	709.22	4.05	252247.63	42.34
C1s	284.06	0	435.57	0.64
O1s	529.9	1.19	103115.2	56.12
Si2s	148.37	0.11	608.94	0.9

Bi_xO_y growth process optimization

Precursor solution:

- [Bi(Ph)₃]=6 · 10⁻³ M in toluene (C₆H₅CH₃)

Bi(Ph)₃ — Bi(C₆H₅)₃ Triphenylbismuth

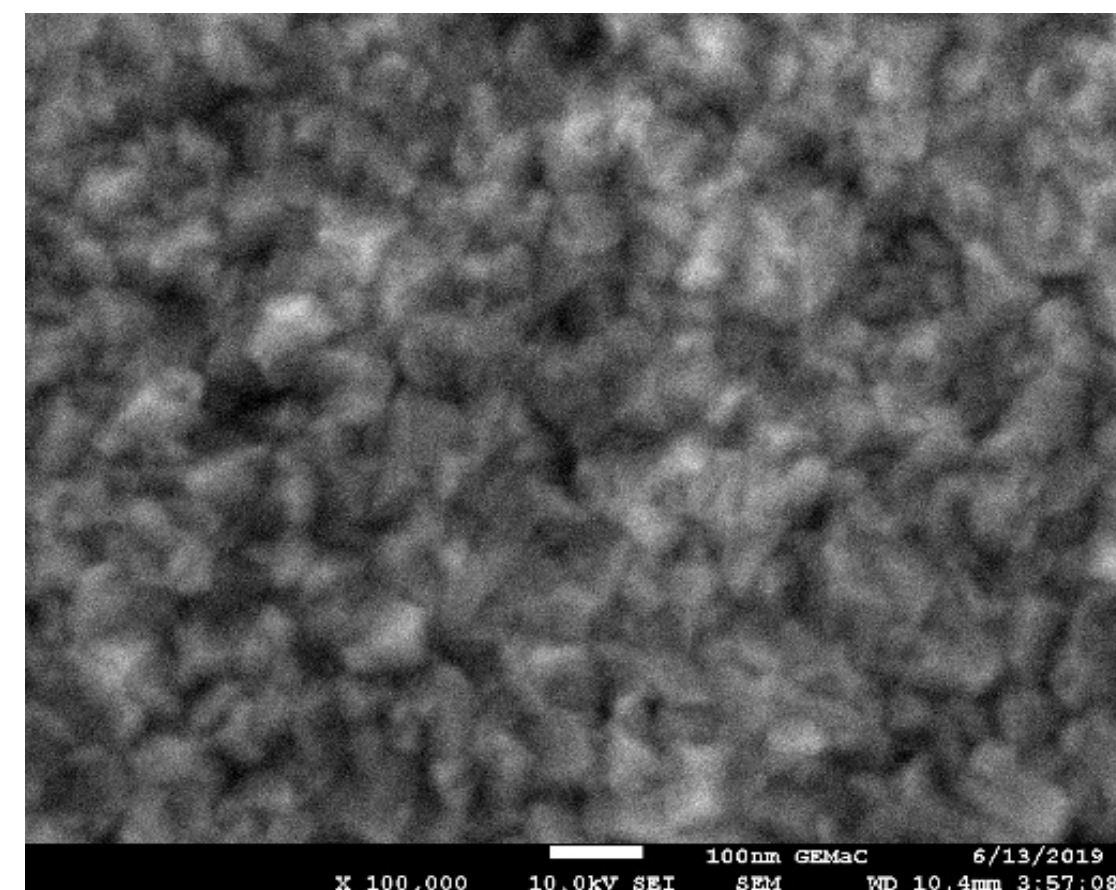
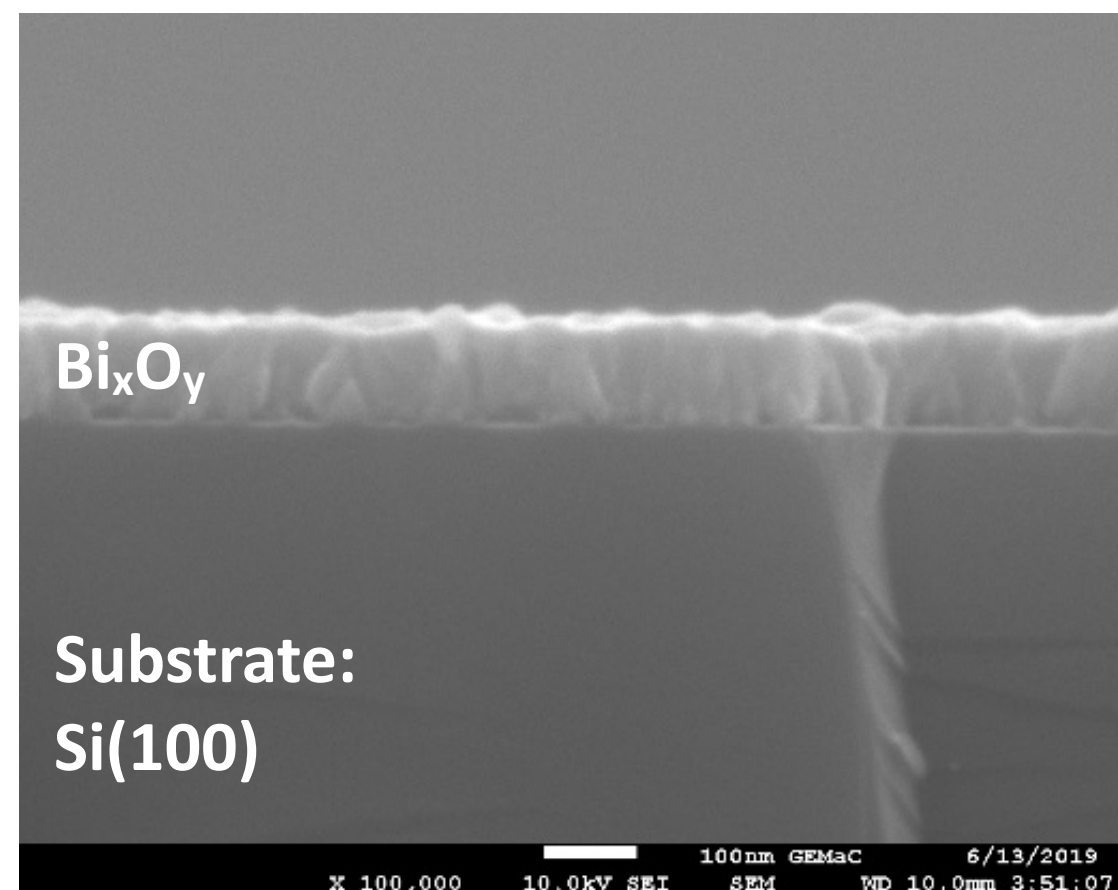
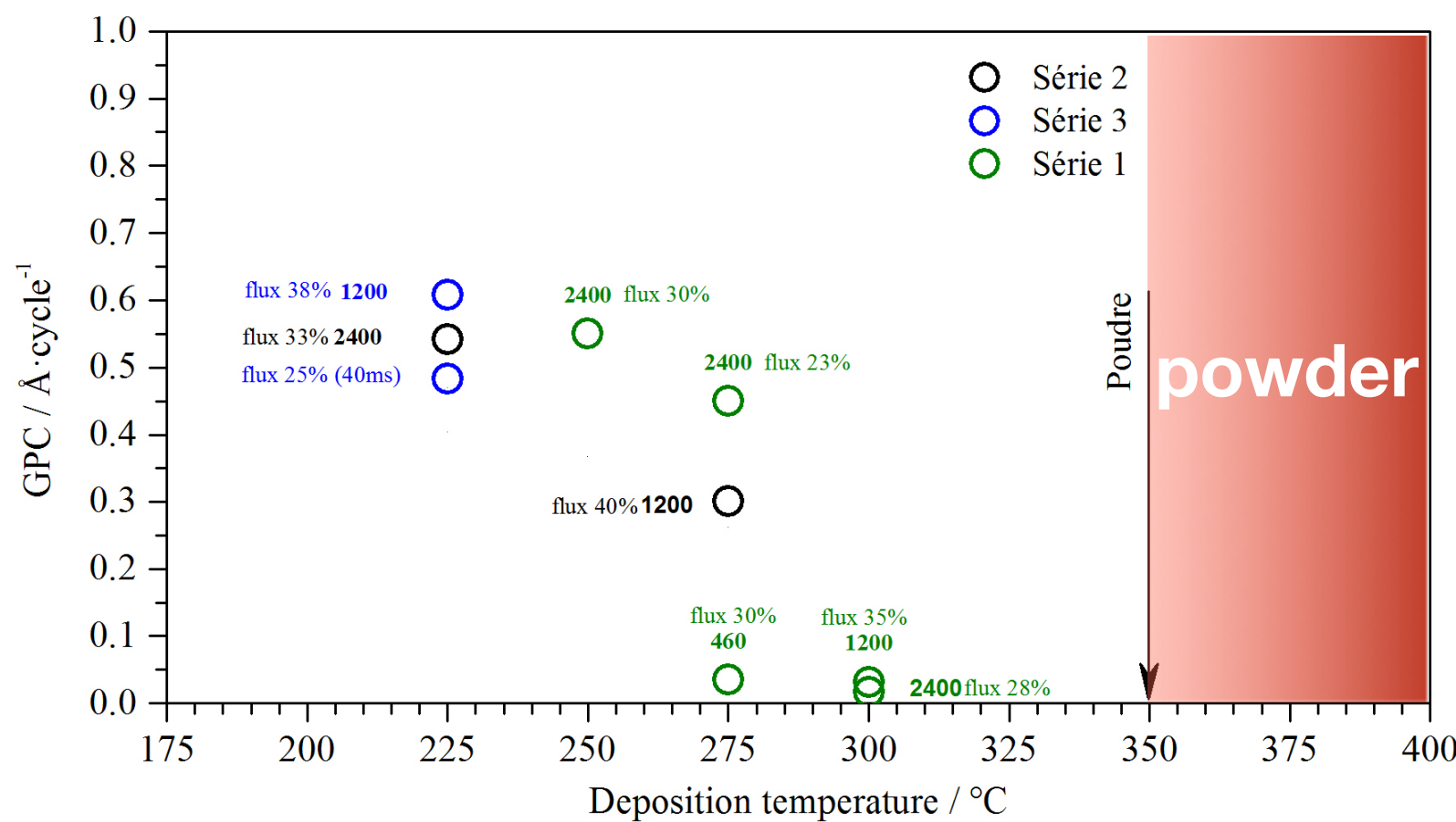
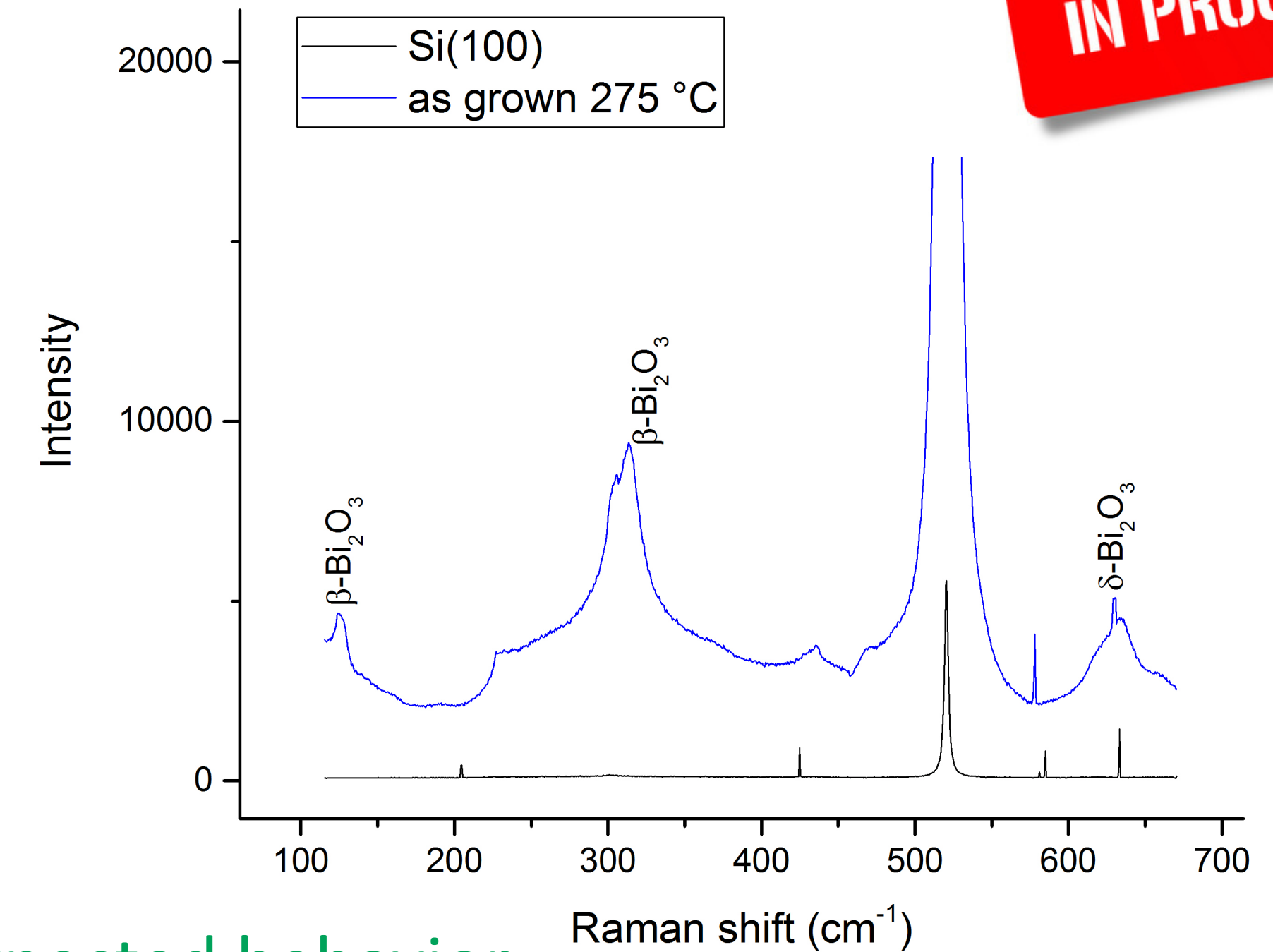
Oxidizing agents: O₃ & H₂O



XPS: O/Bi = 1.716
(1.5 expected for Bi₂O₃)

Name	Peak BE	FWHM eV	Area (P) CPS.eV	Atomic %
O1s phys. spec	/	/	/	/
O1s oxide	528.57	1.44	182062	39.94
C1s	/	/	/	/
Bi 4f5	163.1	1.15	681103	23.27
Bi5d	24.89	1.25	207099	36.79

SEM:
t=225°C
2400 cycles ; ≈80 nm



- unexpected behavior
- no clear ALD window
- non homogenous samples
- Raman: β and γ-Bi₂O₃ without annealing
- non stoichiometric phase(s)
- XPS: no carbon contamination

Conclusions & Perspectives (by the end of 2020)

SrTiO₃ growth

- ✓ optimized TiO₂ DLI-ALD process
- ✓ anatase phase and good homogeneity
- ✓ ALD window for SrO
- ✓ SrO carbon contamination
- ✓ SrTiO₃ obtained after annealing

BiFeO₃ growth

- ✓ optimized Fe₂O₃ DLI-ALD process
- ✓ α-Fe₂O₃ as-grown obtained
- ✓ Bi₂O₃ in progress

Large scale

- ▶ Further optimization of stoichiometry
- ▶ Thermal treatment:
 - *in situ* RTA
- ▶ Si(100) substrate treatment
 - native SiO₂ layer reduction by H₂
 - chemical etching
 - intermediate phase deposition (SrO ?)
- ▶ Phase growth
 - optimisation of stoichiometry (ALD cycle ratio)
 - influence of substrate on phase composition
- ▶ Thermal treatment:
 - as grown crystallization ?
 - post-growth annealing ?
- ▶ 2 inch surface (Si and Ge)
 - homogeneity (phase and thickness)
 - control of interface quality

Acknowledgements

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